Call for Papers

IEEE Open Journal of Instrumentation and Measurement (IEEE OJIM)

Special Section on

Recent Advances in Medical, Biomedical, and Healthcare Measurements

It is well known that measurement is fundamental to medical research and clinical practice. Medical professionals such as doctors, clinicians, or medical laboratory scientists must not only be able to detect and diagnose medical issues but also have confidence in the results reported by their instruments and measurement methods in order to make the correct decision for their patient. In the medical fields, incorrect measurements could be fatal and lead to loss of life; therefore, proper instrumentation and measurement is “vital” in the medical field.

This special section invites papers that present novel methods, instruments, systems, or applications that lie at the intersection of instrumentation and measurement with medical, biomedical, and healthcare fields. This includes instrumentation and measurement related to bioengineering, material science, chemical and biological systems, imaging, as well as medical standards. The covered topics include but are not limited to:

- medical measurement and diagnosis
- measurement and quality control in medical preparations
- measurement in rehabilitation
- acoustics, infrasonics, and ultrasonics medical measurements
- instrumentation and measurement incorporating patient safety
- metrology for medical measurements
- medical imaging and communication
- sensors and devices for medical measurements
- medical instrumentation uncertainty and calibration
- standards for medical applications
- Internet of Medical Things

Each accepted paper for this Special Section will receive an Open Access fee waiver; i.e., accepted papers won’t be charged Open Access fee.

**Deadlines**

Submission:       June 1, 2022  
First decision:   June 25, 2022  
Final decision:  August 5, 2022  
Publication Volume: 2022

For more info and submission instructions, please visit OJIM’s official website: [http://ojim.ieee-ims.org/](http://ojim.ieee-ims.org/)

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